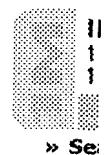


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L1	296	(depth adj reduction)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 18:19
L2	5	(depth adj reduction) and (logic adj gate)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 18:21
L3	2	("4703435").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 18:21
S1	1313	716/18	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 15:04
S2	1574	716/2	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 14:13
S3	1829	716/1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 14:15
S4	772	716/7	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 14:15
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S7	0	(716/18).ccls. and ((adder and comparader) and depth)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 15:05
S8	17	(716/18).ccls. and ((adder and comparat\$) and depth)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 15:06
S9	7	(716/2).ccls. and ((adder and comparat\$) and depth)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 15:06
S10	6	(716/1).ccls. and ((adder and comparat\$) and depth)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 15:06
S11	1	(716/7).ccls. and ((adder and comparat\$) and depth)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 15:07
S12	0	(326/10).ccls. and ((adder and comparat\$) and depth)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 15:08
S13	0	(326/104).ccls. and ((adder and comparat\$) and depth)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 15:08
S14	30	("716"/\$).ccls. and ((adder and comparat\$) and depth)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 15:09
S15	2	("716"/\$).ccls. and ((adder and comparat\$) and depth) and scalable	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 15:11
S16	168	((adder and comparat\$) and depth) and scalable	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 15:14

S17	1	(adder and comparat\$) and (small adj depth) and scalable	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 15:15
S18	0	(small adj depth) and (scalable adj (logic adj circuit))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 15:16
S19	1	(small adj depth) and (scalable adj (logic adj circuits))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 15:16
S20	0	(logic adj circuit) same ((two adj input) adj gate) same depth	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 16:07
S21	92	(logic adj circuit) same (gate) same depth	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 16:29
S22	0	(logic adj circuit) same (gate) same (reduced adj depth)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 16:29
S23	4	(logic adj circuit) same (gate) same (depth adj reduction)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 17:04
S24	9	(logic adj circuit) and (gate) and (depth adj reduction)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 17:14
S25	0	(logic adj circuit) and ((two adj input) adj gates) and (depth adj reduction)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 17:15
S26	0	((two adj input) adj gates) and (depth adj reduction)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/16 18:19



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Vehicular Technology Conference, 1996. 'Mobile Technology for the Human Ra IEEE 46th , Volume: 1 , 28 April-1 May 1996  
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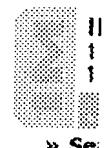
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